

# Contents

Acknowledgements .....	7
Introduction to the Electromagnetic Compatibility of Integrated Circuits .....	19
1. Electromagnetic interference.....	19
2. Electromagnetic environment.....	20
3. Electromagnetic risks for electronic systems .....	22
3.1 ~ Effect of electromagnetic disturbance on radiocommunication systems....	23
3.2 ~ Effect of electromagnetic disturbance on medical devices.....	24
3.3 ~ Effect of electromagnetic disturbance on military systems .....	24
3.4 ~ Effect of electromagnetic disturbance on aeronautical systems .....	25
3.5 ~ Effect of electromagnetic disturbance on automobile systems .....	25
4. What is EMC? .....	26
4.1 ~ Definition.....	26
4.2 ~ Electromagnetic emission.....	26
4.3 ~ Susceptibility and Immunity .....	27
4.4 ~ Noise path .....	28
5. EMC regulations.....	29
5.1 ~ EMC legislation in Europe .....	30
5.2 ~ EMC legislation in the USA.....	32
5.3 ~ Special EMC legislation .....	32
5.4 ~ Evolution of EMC regulations.....	32
6. The EMC of ICs.....	33
6-1 ~ Why address EMC at IC level? .....	34
6.2 ~ A brief history of the EMC of ICs .....	34
6.3 ~ Who is interested in the EMC of ICs? .....	35
7. Scope.....	37
The world of Integrated Circuits .....	41
1. The growth of the Electronics Industry.....	41
2. Increasing Integrated Circuit Complexity .....	43
3. Frequency .....	47
4. MOS Devices .....	48
5. Trends in supply voltage .....	49

- Contents -

6. Input/output Data Rate increase .....	49
7. Roadmap and consequences on EMC .....	50
8. Going 3D .....	51
9. Conclusion .....	53
10. Exercises .....	53
Basic Concepts .....	55
1. Units for EMC .....	55
2. Time and frequency domain representation of signals .....	59
2.1 ~ The art of FFT computing .....	59
2.2 ~ Spectrum of basic signals.....	61
2.3 ~ Fourier Transform of Complex Signals.....	62
2.4 ~ Introducing Noise .....	63
3. Introducing Interconnect .....	66
4. Modelling of interconnects .....	67
5. About the $50 \Omega$ impedance .....	70
6. Using Transmission Lines .....	71
7. Impedance .....	72
7.1 ~ Measurement of Impedance .....	72
7.2 ~ Simulation of Impedance .....	75
7.3 ~ Multiport S and Z matrices .....	76
8. Antenna basics .....	80
8.1 ~ $\lambda/4$ antenna .....	80
8.2 ~ Formulation of Radiation .....	82
8.3 ~ Formulation of radiated coupling .....	84
9. Summary.....	85
10. Exercises .....	85
Overview of EMC issues .....	87
1. Signal Integrity.....	87
1.1 ~ Signal transmission.....	88
1.2 ~ Crosstalk.....	92
2. Power Integrity .....	95
2.1 ~ Definition.....	95
2.2 ~ Target impedance and PDN design control.....	97
2.3 ~ Anti-resonance issue .....	99
3. Conducted emission.....	100

3.1 ~ Definition.....	100
3.2 ~ Differential-mode vs. common-mode current.....	103
4. Radiated emission .....	105
4.1~ Magnetic field antenna .....	105
4.2~ Electric field antenna .....	105
4.3~ Near-field and far-field emission .....	105
4.4 ~ Simple models of radiated emission of a microstrip line.....	108
4.5 ~ Differential and common-mode radiation.....	109
5. Conducted immunity .....	110
5.1 ~ EMI induced failures of analog circuits.....	111
5.2 ~ EMI induced failures of radio frequency circuits.....	112
5.3 ~ EMI induced failures of digital circuits .....	113
5.4 ~ Evaluation of conducted immunity.....	115
6. Radiated immunity .....	118
6.1 ~ Far-field coupling.....	118
6.2 ~ Near-field coupling .....	120
7. Summary.....	121
8. Exercises.....	122
ModelLing passive devices .....	129
1. Chapter objectives .....	129
2. Packages for surface-mount devices .....	130
3. High-frequency electrical modelling of passive devices .....	131
4. Extraction of passive device impedance.....	132
5. Resistors.....	133
5.1 ~ Overview of surface-mount resistor technologies .....	133
5.2 ~ General high-frequency model of a resistor .....	134
5.3 ~ Electrical model of an SMT film resistor .....	134
6. Capacitors.....	137
6.1 ~ Overview of SMT capacitor technologies .....	137
6.2 ~ General electrical model of a capacitor .....	139
6.3 ~ Electrical model of a ceramic capacitor .....	139
6.4 ~ Electrical modelling of an electrolytic capacitor.....	143
a ~ Tantalum capacitor .....	143
b ~ Aluminium capacitor .....	144

- Contents -

7. Inductors and ferrites .....	146
7.1 ~ Overview of SMT inductor and ferrite technologies .....	146
7.2 ~ General electrical model of an inductor.....	149
a ~ Model of a high current inductor .....	150
b ~ Common-mode choke .....	151
7.3 ~ Chip ferrite bead.....	155
8. Summary.....	156
9. Exercises.....	157
ModelLing PCB interconnects.....	161
1. PCB construction overview .....	161
2. Electrical modelling of transmission lines.....	163
3. Per-unit-length parameters of typical PCB traces .....	165
3.1 ~ Microstrip line .....	165
3.2 ~ Edge-coupled microstrip lines.....	169
3.3 ~ Modelling losses .....	172
4. Modelling vias .....	176
5. Modelling power and ground planes .....	178
5.1 ~ Modelling a rectangular power-ground plane pair .....	178
5.2 ~ Application: The IEC61967 board .....	180
6. Summary.....	185
7. Exercises.....	185
EMC Measurement Fundamentals .....	191
1. General principles of EMC measurements .....	191
1.1 ~ Electromagnetic emission measurement principles.....	191
1.2 ~ Electromagnetic susceptibility measurement principles .....	192
2. Usual EMC test facilities .....	195
3. Role of standards .....	196
4. Some examples of EMC measurement at system level.....	196
4.1 ~ Conducted emission measurement.....	197
4.2 ~ Radiated emission measurement in an absorber-lined shielded enclosure .....	199
4.3 ~ Radiated susceptibility measurement in an anechoic chamber.....	200
5. Typical equipment for EMC measurements.....	201
5.1 ~ Spectrum analyser .....	201

5.2 ~ EMI receiver .....	205
5.3 ~ Preamplifier .....	205
5.4 ~ Signal generators .....	205
5.5 ~ Radio frequency power amplifier .....	206
5.6 ~ Bidirectional coupler.....	207
5.7 ~ Power meter .....	208
6. Exercises.....	209
Standard measurement methods for IC emission .....	215
1. Rapid overview of the standard IEC61967 .....	216
2. Conducted emission measurement with IEC 61967-4 - 1 / 150 ohms.....	217
2.1 ~ Conducted emission at IC level .....	217
2.2 ~ RF current measurement – 1 $\Omega$ probe.....	218
2.3 ~ RF voltage measurement - 150 $\Omega$ probe .....	220
3. Radiated emission with IEC 61967-2 - TEM/GTEM cell .....	222
3.1 ~ Description of the TEM cell.....	222
3.2 ~ IC emission measurement with TEM cell.....	224
3.3 ~ Modeling of the coupling between aTEM cell and an IC under test.....	225
3.4 ~ Correlation with far field measurement.....	228
3.5 ~ Suggested emission limits in TEM cell.....	229
3.6 ~ GTEM cell .....	229
4. Near field scan (IEC 61967-3) – Diagnosis at IC level .....	230
4.1 ~ Near-field scanner .....	230
4.2 ~ Near-field probes.....	231
4.3 ~ Near-field probe modeling.....	233
4.4 ~ Examples of near-field measurements above an IC .....	234
5. Exercises.....	235
Standard measurement methods for IC Susceptibility.....	241
1. Rapid overview of standard IEC 62132 .....	241
2. Conducted immunity measurement with IEC 62132-4 – Direct RF Power Injection (DPI) .....	241
2.1 ~ Presentation of the DPI test set-up.....	242
2.2 ~ Bias tee design.....	243
2.3 ~ Power limits in DPI.....	244
2.4 ~ Pin selection for the DPI test.....	244

- Contents -

3. Conducted immunity measurement with IEC 62132-3 – Bulk Current Injection (BCI)	245
3.1 ~ Presentation of the BCI test set-up .....	245
3.2 ~ Modelling the BCI clamp .....	247
3.3 ~ Calibration of the forward power limitation.....	249
3.4 ~ Current limit in the BCI test.....	250
4. Radiated immunity with IEC 62132-2 – TEM and GTEM cells .....	251
4.1 ~ IC immunity measurement with a TEM cell.....	251
4.2 ~ Modelling a TEM cell radiated susceptibility test.....	252
4.3 ~ Maximum electric field in a TEM cell test.....	254
5. Radiated immunity with IEC 62132-8 – IC stripline.....	255
6. Exercises.....	256
IntegrateD Circuit Packaging and Interfaces .....	261
1. Package technology .....	261
2. Inside a BGA .....	264
3. Going 3D .....	266
4. Different types of I/Os.....	269
5. IBIS model for I/O EMC issues .....	271
6. Exploiting IBIS for EMC simulation .....	276
6.1~ Convert an input into an RLC diagram.....	276
6.2 ~ Protection Diode Modelling .....	276
6.3 ~ Converting an output.....	278
6.4 ~ Buffer simulation.....	281
7. Conclusion .....	288
8. Exercises.....	289
Modelling IC emission .....	293
1. Using models to predict the EMC performance of ICs .....	293
2. The IEC 62433 project .....	294
3. ICEM-CE model .....	295
3.1~ Definitions .....	295
3.2~ Getting Started.....	296
3.3~ Applying basic guidelines .....	299
3.4~ Matching measurements .....	300
3.5~ A more complex ICEM-CE model.....	301
3.6~ Modelling internal activity .....	302

a~ Evaluating IC complexity.....	303
b~ Extract the maximum transient current .....	306
c~ Estimate the realistic current.....	308
4. Case study – 16-bit microcontroller.....	310
4.1~ EMC test board .....	310
4.2~ IBIS information .....	312
4.3~ Power distribution network modelling .....	314
4.4~ Conducted emission.....	316
a~ Conducted emission modelling in “Core Only” mode .....	316
b~ Conducted emission modelling in “PortB Active” mode .....	318
c~ Radiated emission modelling in a TEM cell.....	324
5. Conclusion .....	326
6. Exercises.....	326
ModelLling IC susceptibility - Basic concepts.....	331
1. General structure of an integrated circuit susceptibility model .....	331
1.1 ~ PDN modelling .....	333
a ~ Definition and construction .....	333
b ~A simple approach for assessing circuit susceptibility.....	334
1.2 ~ Modelling non-linear parts of the PDN .....	335
1.3 ~ Modelling circuit behaviour in response to electromagnetic disturbance	338
a ~ "White-box" approach.....	339
b ~ "Grey-box" approach.....	339
c ~ "Black-box" approach .....	339
2. IEC 62433-4 - The ICIM-Cl model proposal .....	340
3. Susceptibility simulation with IC-EMC.....	342
3.1 ~ General presentation of the simulation flow .....	343
3.2 ~ RFI source .....	345
3.3 ~ Detecting a failure .....	345
3.4 ~ Example: conducted injection into a fixed load .....	347
4. Case study 1 - Modelling the propagation of an external disturbance within an integrated circuit.....	349

- Contents -

4.1 ~ Presentation of the case study.....	349
4.2 ~ Board modelling .....	351
4.3 ~ Modelling the PLL's PDN .....	352
4.4 ~ Simulation of the voltage coupled to the VCO power supply.....	355
5. Case study 2 - Simulation of the susceptibility of a digital I/O port.....	358
5.1 ~ Set-up for disturbing the I/O port.....	358
5.2 ~ Measurement results.....	360
5.3 ~ I/O susceptibility model structure.....	360
5.4 ~ Simple model: coupling path model.....	361
5.5 ~ Complex model: realistic IC model .....	363
a ~ Input buffer model .....	363
b ~ Power supply network model.....	365
c ~ Simulating I/O susceptibility .....	366
6. Summary.....	367
7. Exercises.....	368
Glossary.....	373
Getting started with ic-emc.....	375
1. IC-EMC - An overview.....	375
2. Installing and running IC-EMC.....	376
2.1 ~ Download the Schematic Editor.....	376
2.2 ~ Download WinSpice.....	377
2.3 ~ Initial Screen .....	377
2.4 ~ Close WinSpice .....	378
2.5 ~ Close IC-EMC.....	378
3. Presentation of the menus and component palette .....	378
3.1 ~ Overview of the menus .....	378
3.2 ~ Symbol palette .....	381
3.3 ~ Main EMC commands.....	382
4. Using IC-EMC .....	383
4.1 ~ Overview of the modelling and simulation flow.....	383
4.2 ~ Example - Simulation of the conducted emission of a microcontroller....	383
a ~ Open the example .....	383
b ~ Current Source Description .....	385

c ~ Power supply Description .....	386
d ~ Analysis Description .....	386
e ~ Create the SPICE file .....	387
f ~ Run SPICE Simulation .....	388
g ~ Emission simulation .....	388
h ~ Comparison with Measurements .....	389
5. On-line documentation .....	390